



MONDAY 23 MAY 2016 – Workshop WMC

Power and Signal Integrity Characterization Techniques

MOSCONE CENTER • SAN FRANCISCO, CALIFORNIA, USA



Power and Signal Integrity Characterization Techniques

Organizer: Heidi Barnes, *Keysight Technologies*, Ken Wong, *Keysight Technologies*, Mike Resso, *Keysight Technologies*.

Abstract: Many technology companies must design and develop highly complex chips, packages, and boards for telecom and datacom applications. Issues of power and signal integrity arise from a steady increase in IC speed and data transmission rates combined with a steady decrease in power-supply voltages. The latest applications from cloud computing to the Internet of Things force these new designs into smaller geometries and with higher densities. The integration of numerous I/O counts, multiple stacked chips and packages, and higher electrical performance requirements go far beyond simple schematic netlists to determine performance. Modern electro-magnetic simulations and RF/uW measurement techniques are increasingly being applied to these complex 3D distributed systems. Breakthrough solutions based on intuitive understanding of fundamental power integrity and signal integrity characterization techniques can help the design engineer overcome these challenges. This workshop will present multiple perspectives from experts in the field starting with theoretical fundamentals through practical real world design case studies.

1. I Know Signal Integrity, I Have Heard of Power Integrity, but What is SI/PI Co-Simulation?
Heidi Barnes; *Keysight Technologies*
2. The Bandini Mountain, a pathological problem in PDN Design
Eric Bogatin; *University of Colorado*
3. Power Integrity Challenges in the Race for Small Size and High Efficiency Power Delivery
Steven Sandler; *PicoTest*
4. Today's Power Integrity Issues with FPGA Applications
Jack Carrel; *Xilinx, Inc.*

Registration

This event is a half-day workshop. You can find the registration rates on the IMS 2016 web site [here](#).

Registration procedure is [there](#).